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Application/Control No	Applicat	ion/Co	ntrol	No.
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Applicant(s)/Patent under Reexamination

10/645,670

SHIMOMURA ET AL.
Art Unit

Examiner

2818

Long K. Tran

SEARCHED					
Class	Subclass	Date	Examiner		
345	31,39	10/26/2005	LKT		
340	815.45	10/26/2005	LKT		
340	815.53	10/26/2005	LKT		

INI	ERFEREN	CE SEARCH	ED		

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
		-				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
257/88,89,98 (text search only; see search history printout)	10/26/2005	LKT		
Interference Search History Printout	10/26/2005	LKT		
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